HIGH PERFORMANCE SRAM CIRCUIT BASED ON TRANSMISSION GATE USING FinFET AND ADIABATIC LOGIC

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Abstract: In this paper, a high speed, low power dissipation, low average power consumption and low PDP (Power Delay Product) based SRAM cell is proposed. SRAM cell play an important role in storage devices and hence it is necessary to produce a better design for the optimal use in the portable devices. The MOSFET based conventional 6 T SRAM has high power and delay product with high short channel effects in 32nm technology. Hence, a solution is provided by the use of adiabatic logic and transmission gate logic. In this technique, use a transistor between Vdd and Virtual Vdd to improve the characteristics, it shows that Average power is decreased by 94.75%, delay is improved by 87.15%, power dissipation is improved by 88.78% and energy is decreased by 99.19% in adiabatic proposed circuit when compared to adiabatic FinFET based circuit and similarly the improvements in transmission gate based proposed circuit from simple transmission gate FinFET SRAM is improved by 55.24%, 50.28%, 68.63% and 75% on basis of Average Power, Delay, Power Dissipation and Energy. The proposed circuits is of 8 Transistors.

Keywords: - FinFET, 32nm Technology, SRAM, Low Power

I. INTRODUCTION

Memory cells assume a critical job regarding force, speed and execution in computerized circuits, for example, the System-on-Chips (So Cs), microchips and microcontrollers. These memory clusters possess impressive piece of the chip region. Consequently, these memories. Cells as a general rule contribute for a higher division of the chip control. A few literary works have exhibited different designs for the SRAM cell, with their principle centre around decrease of the cell territory, diminished gadget include and decrease in the spillage control. The preference to optimize the layout metrics of overall performance, strength, area, fee, and time to market (opportunity cost) has now not changed for the reason that progress of the IC enterprise. Advantage of FinFET contrasted with planar is way higher execution at a proportionate power spending plan, or equivalent execution at a far lower power spending plan. This basically gives originators the power to extricate the best execution for very shoddy power, a urgent improvement for powered gadgets. One element that creates the progress from thinking of with planar FETs to concocting with FinFET somewhat less confused is that the demonstrated actuality that the back-end of the strategy is essentially a proportional, piece of the arranging stream identified with the physical execution stays flawless.

II. IMPLEMENTATION

In this section, we propose the circuits for adiabatic and transmission gate logic based 9T SRAM cells. The circuit consists of one p type FinFET at VDD part of the base circuit. The circuit is controlled by the signal given in this circuit. The circuit is simulated in HSPICE Synopsys and the technology used 32nm.

Proposed Adiabatic based FINFET Circuit:

In the figure 1, the adiabatic logic is created by the use of MCPL logic, and also at Vdd an extra control transistor is added which decides when the circuit is on or off. The makes it in sleep or active mode.

Proposed Transmission Logic based FINFET Circuit:

In the figure 2, the transmission gate logic is created by the use of two transistors at WBL and ABL bar, and also at Vdd an extra control transistor is added which decides when the circuit is on or off. The makes it in sleep or active mode.



Figure 1: Proposed Adiabatic based SRAM cell FinFET



Figure 2: Transmission Gate Logic Proposed Circuit for SRAM

III. RESULTS

The results of the performance parameters are shown in fable 1 which clearly shows the enhancements in proposed circuits.

Table 1: Simulation Results				
		sram adiabatic mos		sram adiabatic fin
	sram adiabatic mos	proposed	sram adiabatic fin	proposed
Average Power	1.25E-07	1.04E-07	4.63E-09	2.43E-10
Delay	1.41E-07	1.41E-07	7.27E-11	9.34E-12
Power Dissipation	1.79E-07	1.06E-07	1.23E-11	1.38E-12
Energy	1.75E-14	1.46E-14	3.37E-19	2.27E-21
		sram TGL mos		sram TGL fin
	sram TGL mos	proposed	sram TGL fin	proposed
Average Power	3.07E-08	7.08E-09	5.23E-12	2.55E-12
Delay	5.17E-11	3.33E-12	5.10E-11	2.60E-11
Power Dissipation	9.87E-08	8.57E-08	5.26E-12	1.65E-12
Energy	1.59E-18	2.36E-20	2.66E-22	6.65E-23

In figure 3 and Figure 4 shows the Average Power in Various circuits for adiabatic and transmission logic gate based. The proposed circuits shows better performance in Average Power Consumption.3





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Figure 6: Power Dissipation in Adiabatic based Circuits

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Figure 7 and Figure 8 Energy in Adiabatic and Delay in transmission gate logic circuits in SRAM FinFET are represented.







Figure 10: Energy in TGL based Circuits

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ISSN: 2393-9028 (PRINT) | ISSN: 2348-2281 (ONLINE)

Figure 9 and Figure 10 shows the Power Dissipation and Delay in TGL based circuits and shows that Proposed circuit is improved the performance.



Figure 11 shows the waveforms for the TGL based circuits, the SRAM stores 0 and 1 efficiently.



Figure 12 shows the waveforms for the Adiabatic based circuits, the SRAM stores 0 and 1 efficiently.

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IV. CONCLUSION

Hence, we conclude that by use of transistor between VDD and the circuit virtual Vdd will improve the characteristics and performance of the circuit. The proposed circuit consists of 9T based FinFET. The improvement in the circuit are follows: In adiabatic SRAM proposed circuit:

- Average power is decreased by 94.75%,
- delay is improved by 87.15%,
- power dissipation is improved by 88.78% and
- energy is decreased by 99.19%
- In transmission gate based proposed circuit improvements are:
- 55.24% in Average Power
- 50.28% in Delay
- 68.63% in Power Dissipation
- 75% in Energy

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